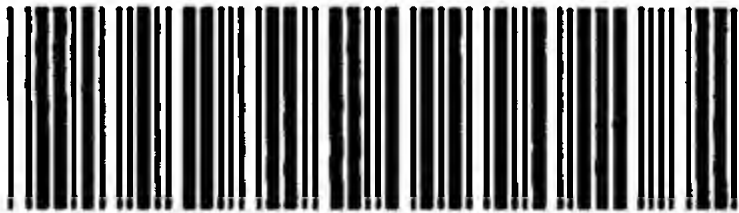


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,823	CHANG CHIEN ET AL.	
	Examiner	Art Unit	
	Tanh Q. Nguyen	2182	

SEARCHED			
Class	Subclass	Date	Examiner
710	62-64, 72-74 100, 300, 305 306	05/04/07 05/05/07	TQU ✓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
invariant search. eDAN/East East search. Results attached	05/04/07 05/04/07 05/05/07 05/09/07	TQU ↓